

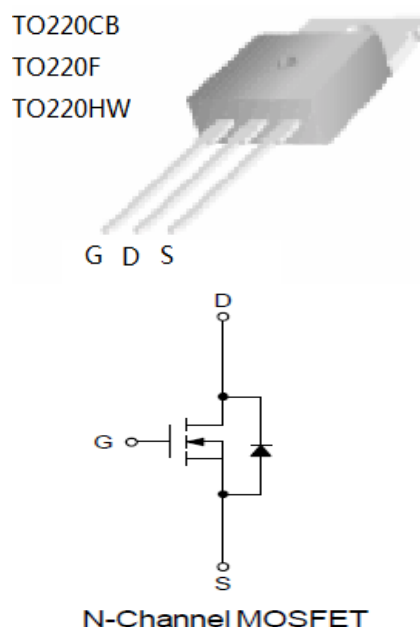
POWER MOSFET

Features

- 75V,80A N-Channel MOSFET
- $R_{DS(on)(typ.)}=6.5m\Omega @V_{GS}=10V, I_D=40A$
- High ruggedness
- Fast switching
- 100% avalanche tested
- Exceptional dv/dt capability

Applications

- Switching application



Absolute Maximum Ratings

Symbol	Parameter	Value	Units
V_{DSS}	Drain-Source Voltage	75	V
V_{GS}	Gate-Source Voltage	+25	V
I_D	Continuous Drain Current($T_C=25^\circ C$)	80	A
	Continuous Drain Current($T_C=100^\circ C$)	70	A
I_{DM}	Pulsed Drain Current(Note 1)	360	A
EAS	Single Pulsed Avalanche Energy(Note 2)	1200	mJ
P_D	Maximum Power Dissipation ($T_C=25^\circ C$)	300	W
	Maximum Power Dissipation ($T_C=100^\circ C$)	150	W
T_J	Operating Junction Temperature Range	-55 to +150	$^\circ C$
T_{STG}	Storage Temperature Range	-55 to +150	$^\circ C$

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. Starting $T_J=25^\circ C, L=1.0mH, R_G=25\Omega, I_D=37A, V_{GS}=10V$

Thermal data

Symbol	Parameter	Max.	Units
$R_{th\ J-C}$	Thermal Resistance, Junction to case	0.6	$^{\circ}C/W$

Electrical Characteristics ($T_C=25^{\circ}C$ unless otherwise noted)

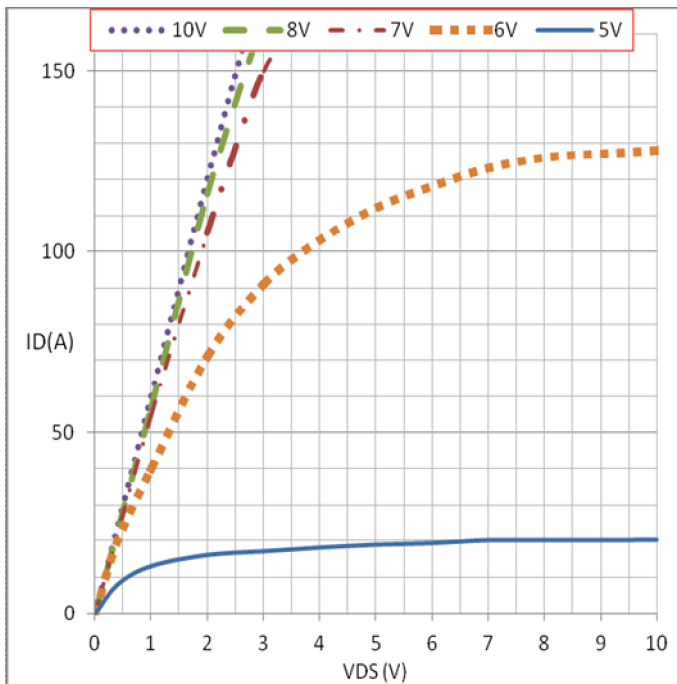
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	75			V
I_{DSSS}	Drain-Source Leakage Current	$V_{DS}=75V, V_{GS}=0V$			1	μA
I_{GSS}	Gate Leakage Current, Forward	$V_{GS}=25V, V_{DS}=0V$			100	nA
	Gate Leakage Current, Reverse	$V_{GS}= -25V, V_{DS}=0V$			-100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}=V_{DS}, I_D=250\mu A$	2	3	4	V
$R_{DS(on)}$	Collector-Emitter Saturation Voltage	$V_{GS}=10V, I_D=40A$		6.5	9	m Ω
gfs	Forward Transconductance	$V_{DS}=15V, I_D=30A$		28		S
Q_g	Total Gate Charge	$V_{DD}=60V$ $V_{GS}=10V$ $I_D=40A$		89	120	nC
Q_{gs}	Gate-Source Charge			21		nC
Q_{gd}	Gate-Drain Charge			33		nC
$t_{d(on)}$	Turn-on Delay Time	$V_{DD}=40V$ $V_{GS}=10V$ $I_D=40A$ $R_G=5\Omega$	-	47	-	ns
t_r	Turn-on Rise Time		-	25	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	75	-	ns
t_f	Turn-off Fall Time		-	36	-	ns
C_{iss}	Input Capacitance	$V_{DS}=30V$ $V_{GS}=0V$ $f = 1MHz$	-	3600	-	pF
C_{oss}	Output Capacitance		-	480	-	pF
C_{rss}	Reverse Transfer Capacitance		-	180	-	pF
R_{Gint}	Integrated gate resistor			1.24		Ω

Source-Drain Ratings and Characteristics ($T_C=25^{\circ}C$ unless otherwise noted)

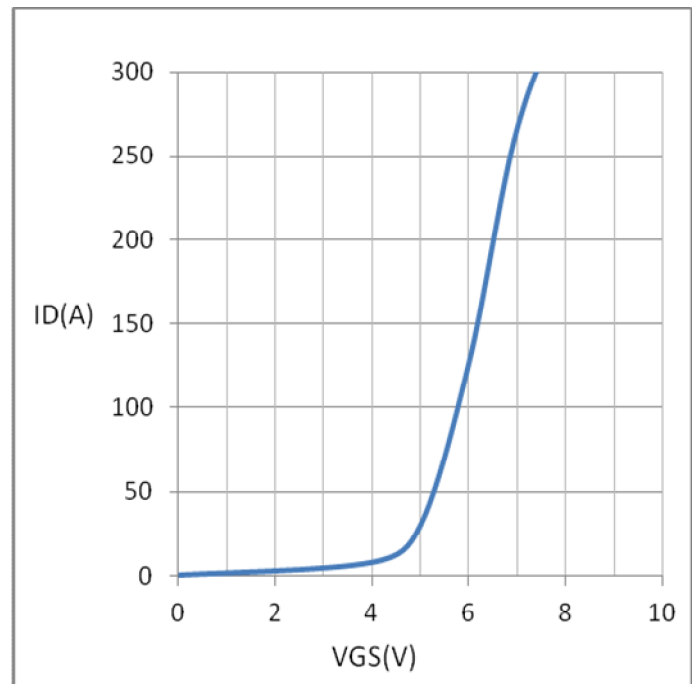
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage	$V_{GS}=0V, I_S=40A$	-	0.88	1.2	V
I_S	Continuous Diode Forward Current				80	A
t_{rr}	Reverse Recovery Time	$V_{DD}=25V, I_S=40A$ $dI_F/dt=100A/\mu s$	-	64		ns
Q_{rr}	Reverse Recovery Charge		-	138		nC

Typical characteristics

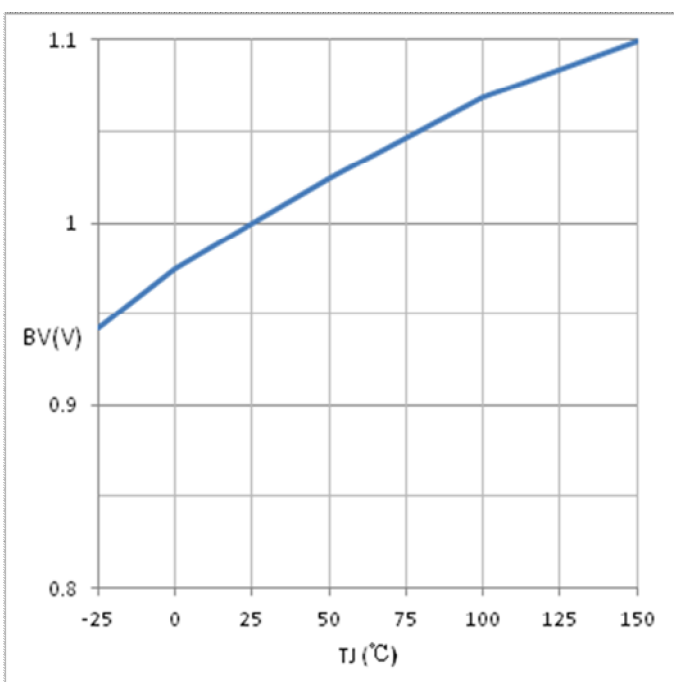
Output characteristics



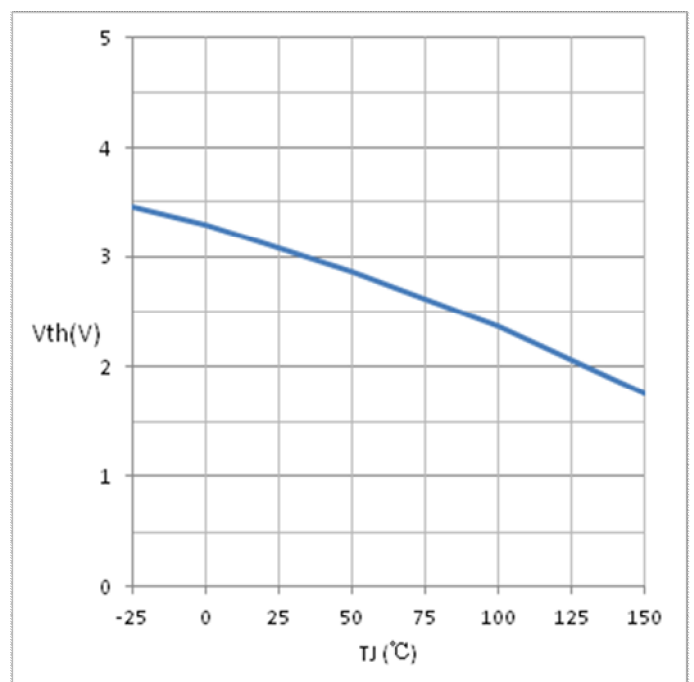
Transfer characteristics



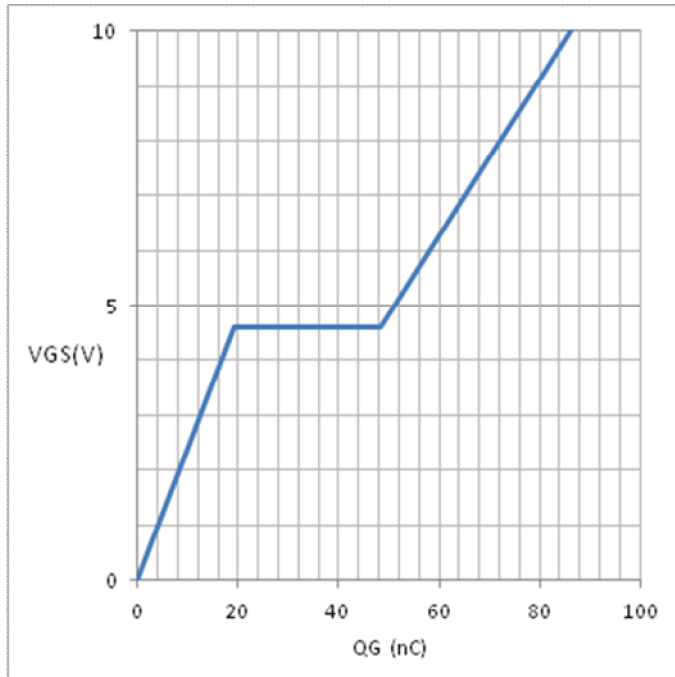
Normalized Bvdss vs temperature



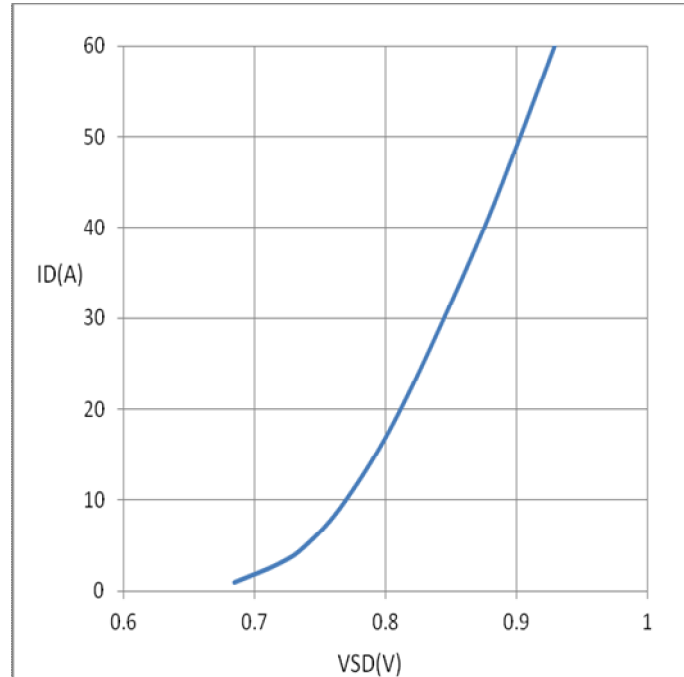
Vth vs temperature



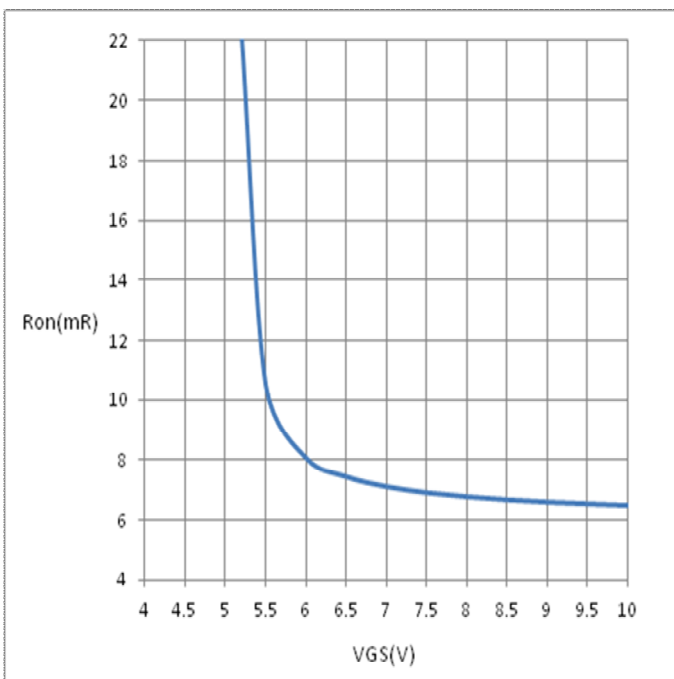
Gate charge vs Gate-source Voltage



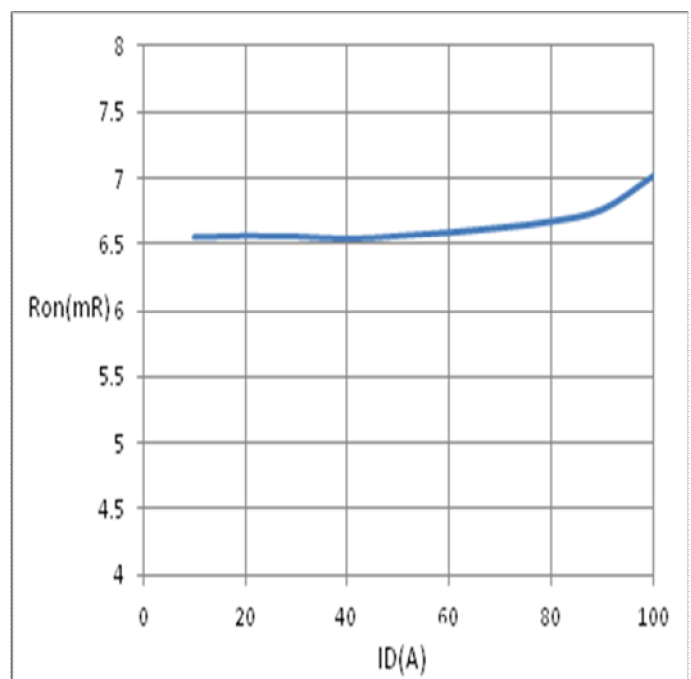
Source-drain diode forward



Drain-source on resistance vs Vgs

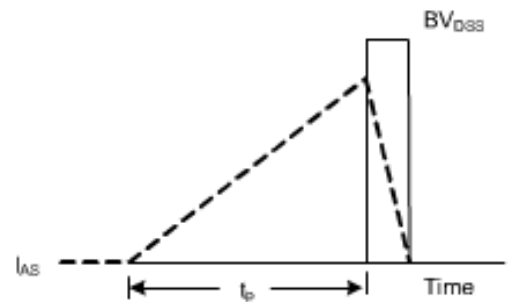
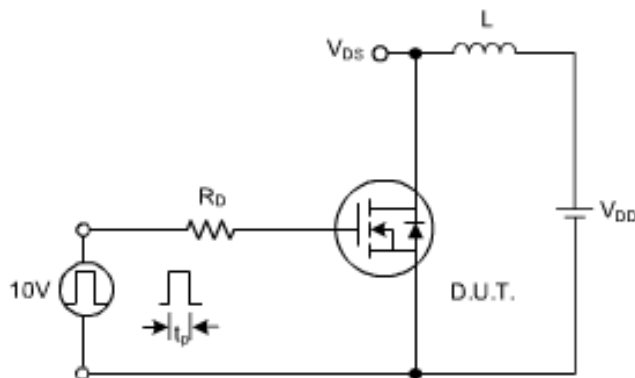


Drain-source on resistance vs ID

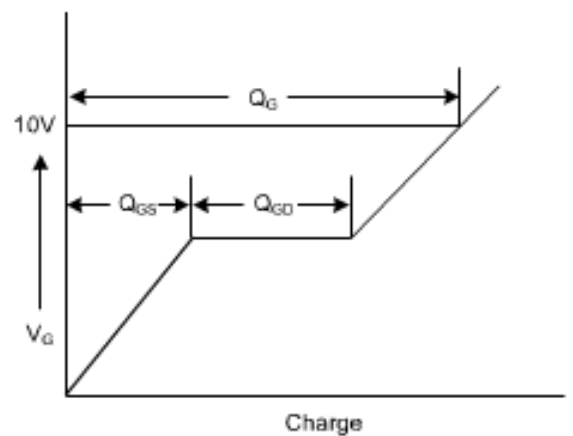
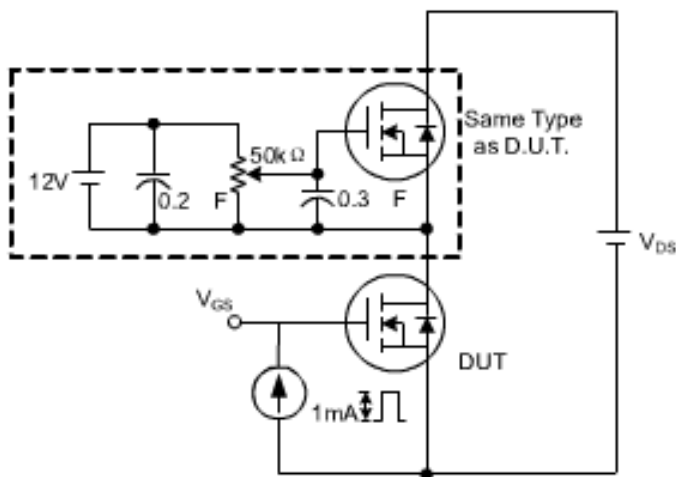


Test Circuits

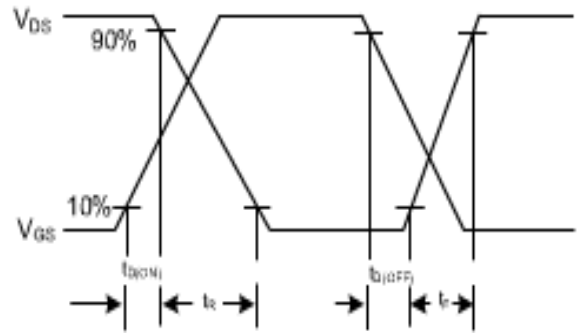
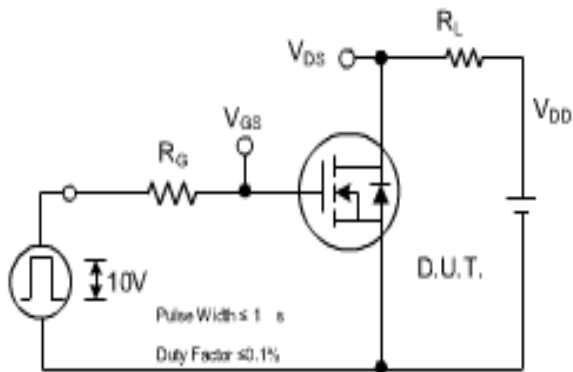
Avalanche test circuits and waveforms



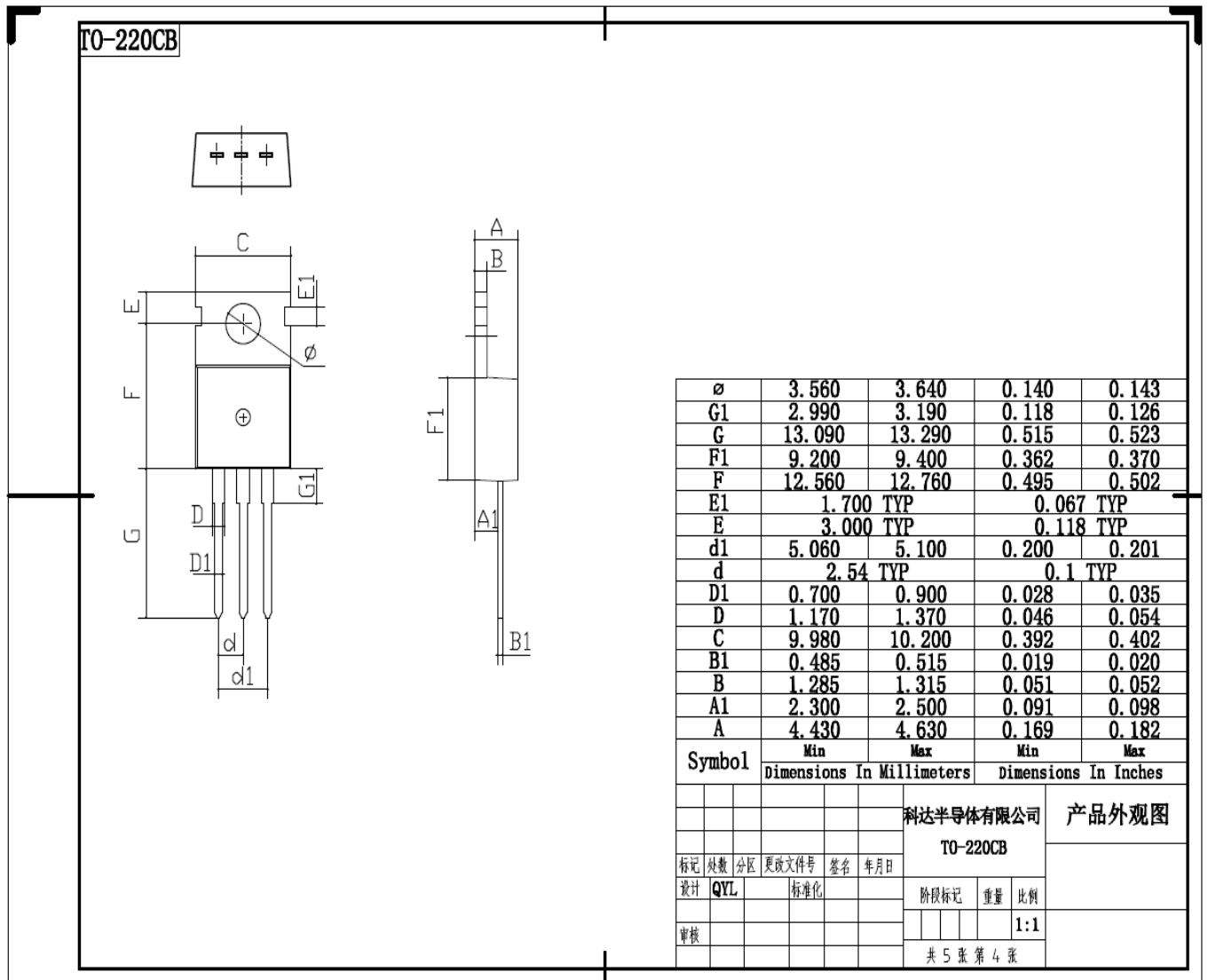
Gate charge test circuits and waveforms



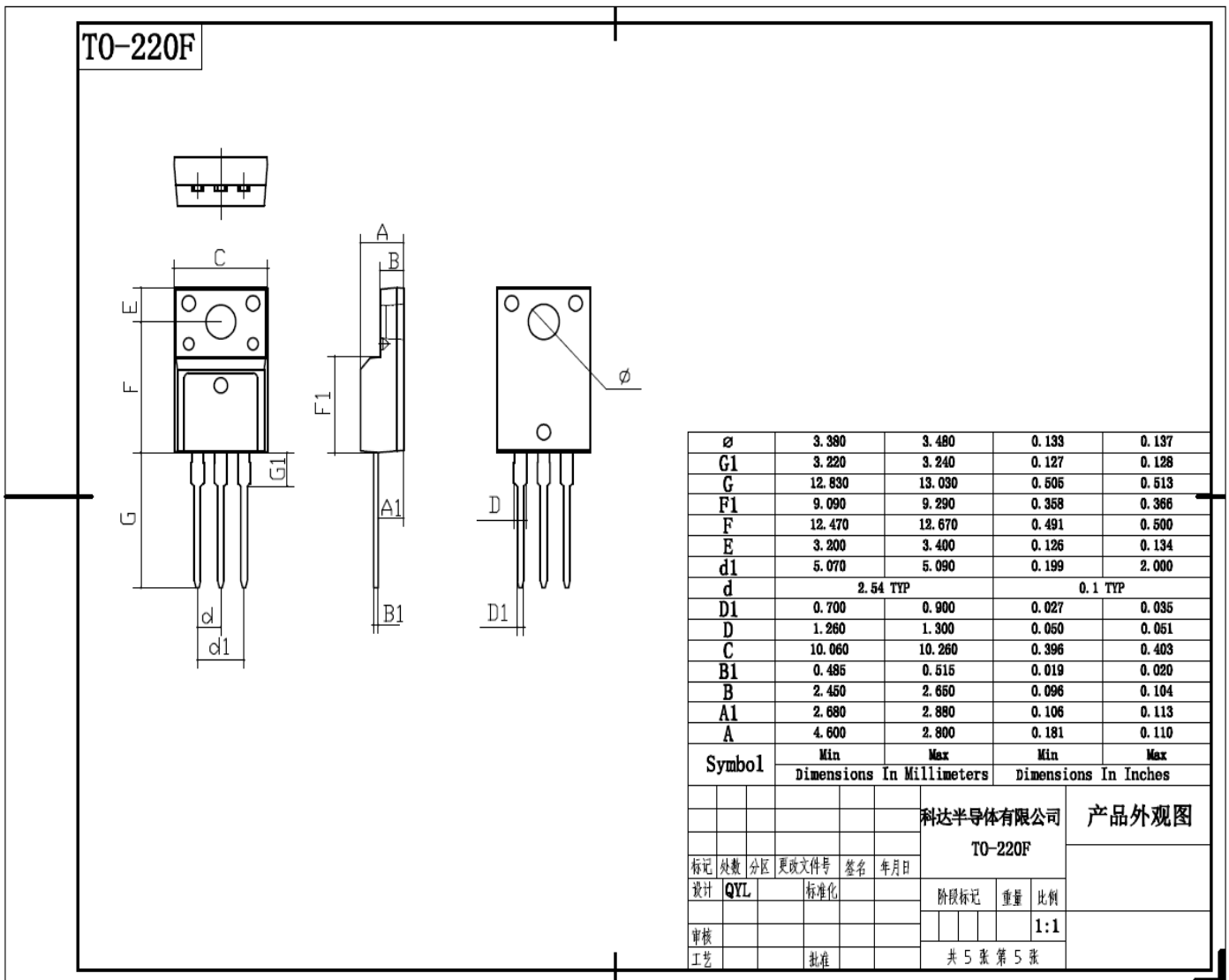
Switching time test circuits and waveforms



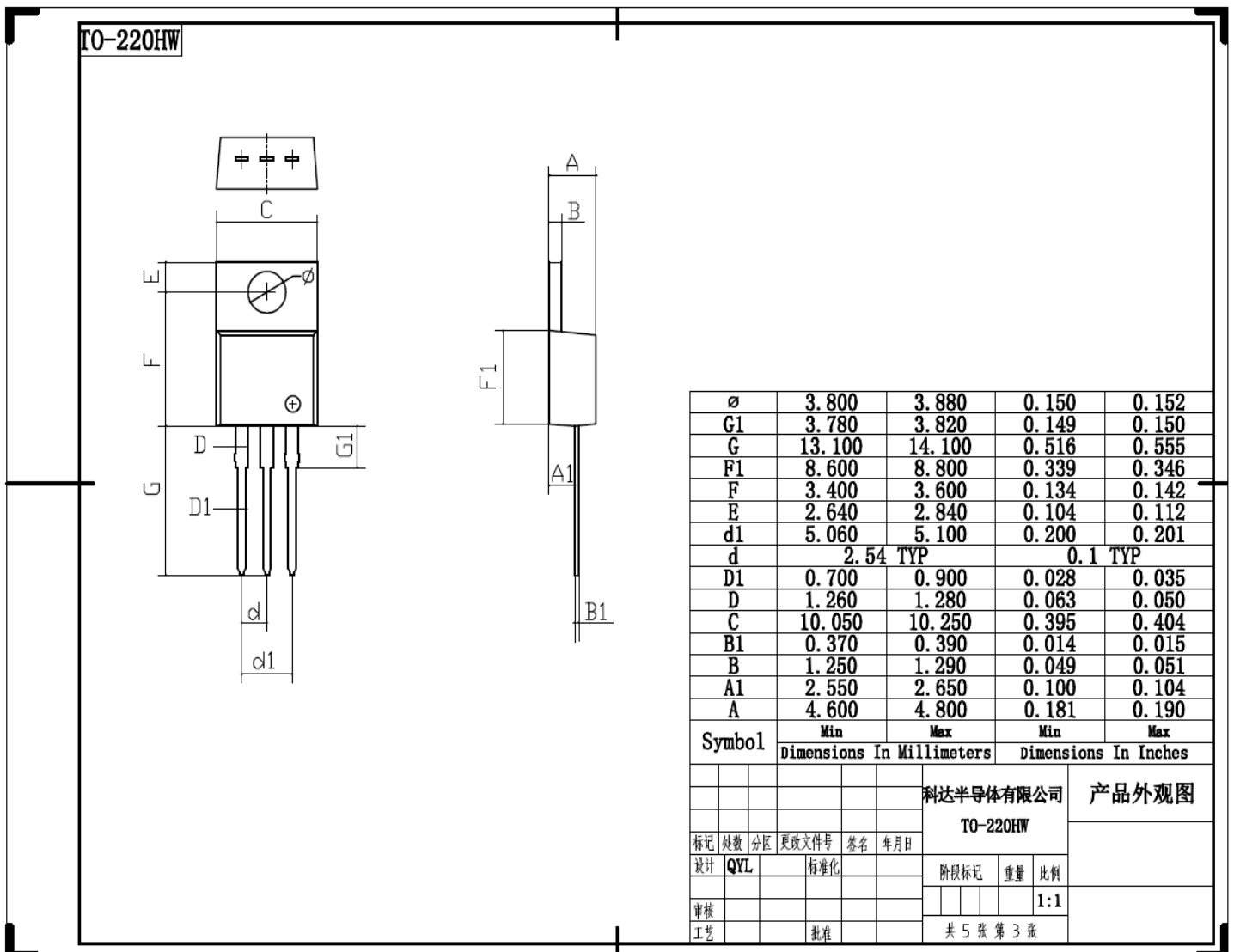
TO220CB package outline



TO220F package outline



TO220HW package outline



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